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<b>Form 1449 (Modified)</b>  <b>Information Disclosure Statement By Applicant</b>  (Use Several Sheets if Necessary)	Atty Docket No. NOVLP014/NVLS-000388	Application No.: 09/833,385
	Applicant: Mukul Khosla	
	Filing Date April 11, 2001	Group 1741

**U.S. Patent Documents**

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub- class	Filing Date

**Foreign Patent or Published Foreign Patent Application**

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub- class	Translation	
							Yes	No

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**Other Documents**

TC 1700

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
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UW.	C	Paar, Anton, "L-DENS-Liquid Density Transmitter for OEM Applications (Original Equipment Manufacturer)", Instruction Book, March 12, 1996, pp. 1-30.
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UW.	F	"Real Time Analyzer (RTA) Technical Manual", Technic, of Providence, Rhode Island, pp. 1-19. **
Examiner	Date Considered	
UW.	8/6/03	

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

\* No month avail

\*\* No Date Avail.



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**U.S. Patent Documents**

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
U4.	A	5,352,350	10/04/94	Andricacos et al.			

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**Other Documents**

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